Agenda, 1st Day
Monday, 7th of February

Time	Item
12:30	Transportation Pick up at LNE Paris
13:30	Registration at LNE Entrance
14:00	Welcome and Introduction
15:00	**Introduction about Nanometrology**
15:30	Metrological AFM State of the art
16:00 17:30	**Topic 1 – Metrology Frame & Thermal Design** 5 talks (20 min)
17:30	*Coffee Break and Poster installation*
18:00	*End*
18:15	Transportation to LNE Paris

Agenda, 2nd Day
Tuesday, 8th of February

Time	Item
08:30	Transportation Pick up at LNE Paris
09:30 11:00	**Topic 2 – Interferometry & Traceable Measurements** 5 talks (20 min)
11:00	*Coffee Break*
11:30 13:00	Poster Session
13:00	*Lunch Break*
14:00 15:30	**Topic 3 – Actuation & Guidance** 5 talks (20 min)
15:30	*Coffee break*
16:00 17:30	**Topic 4 – Electronics, Control & Data Acquisition** 5 talks (20 min)
17:30	*End*
17:45	Transportation to LNE Paris
20:00	Workshop Dinner in Paris

Agenda, 3rd Day
Wednesday, 9th of February

Time	Item
08:30	Transportation Pick up at LNE Paris
9:30 11:00	**Topic 5 – Budget Uncertainty & Calibration** 5 talks (20 min)
11:00	*Coffee Break*
11:30 12:30	**Topic 6 – Industrial Needs & European Projects** 3 talks (20 min)
12:30	Conclusion & Closing
13:00	*Lunch Break*
14:30	*Lab Tour @ LNE*
17:00	*End*
17:15	Transportation to LNE Paris

Scope of the workshop

Nanotechnology is today expected to have a tremendous impact on our societies. Because of a strong correlation between physical properties and dimensions of nano-objects, it represents an unprecedented engineering opportunity to specially design the properties of materials for their particular application.

To bring nanotechnologies through a successful business, (nano) metrology is necessary as the key discipline to enable the exchange and comparison of industrial/academic products, components and measurement results. Thus, it's necessary to provide some relevant metrology tools with ability to measure in three dimensions with sub-nanometric resolutions and uncertainties.

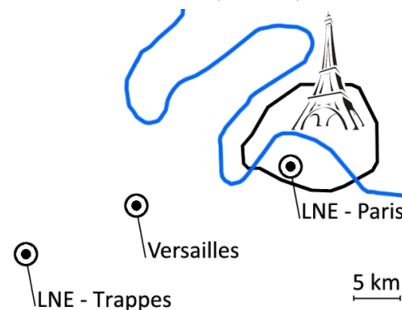
Scanning probe microscopes fulfil parts of those needs in nanometrology. Since the end of the eighties, two generations of metrological AFMs have been building: it's a large collection of instruments with an original arrangement of different technical solutions for a common purpose: the practice of metrology at the nanometer scale.

The aim of this workshop is to provide an overview of the developments about instrumentation relative to metrological AFMs and also the practice of nanometrology by AFM. It will be the opportunity to discuss the technical choices, problems and solutions relative with this instrumentation. The workshop is organized through several sessions with some specific topics illustrated by oral presentations and followed by round tables.

Contact & Location

Location

The workshop will take place at the Trappes LNE site, in the west Paris suburban (30 km).



Access

Participants will be shuttled every morning and evening by special bus between the Paris and Trappes LNE sites.

Hotels

Participants are responsible for reserving their own accommodation – see the joined hotel list.

Fees

The fee will be 100 € (taxes excluded) and will include proceedings, beverages, lunch during the workshop and the Workshop Dinner – see the joint registration form.

Registration

Please register online at:
www.french-metrology.com/mafm-workshop

Contact

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Metrological AFMs workshop

Workshop on Metrological Atomic Force Microscope Instrumentation

From

7th – 9th of February 2011

Organizers

B. Poyet (LNE) and S. Ducourtieux (LNE)

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